

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10764200	LEE ET AL.
	Examiner	Art Unit
	Wiehe, Nathan	3745

SEARCHED

Class	Subclass	Date	Examiner
415	186,189,208.1,209,211.2,213.1,214.1	5/28/2007	NEW
416	244R	5/28/2007	NEW
above	updated	10/18/2007	NEW

SEARCH NOTES

Search Notes	Date	Examiner
415/186,189,208.1,209,211.2,213.1,214.1 416/244R Igor Kershteyn	5/28/2007	NEW
Text Search (See EAST Search History)	5/28/2007	NEW
Inventor Name Search	5/28/2007	NEW
above updated	10/18/2007	NEW

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner